Electronic Supplementary Material (ESI) for Journal of Materials Chemistry

Supporting Information

Mechanism of a AZO-coated FTO Film in Improving the Hydrogen Plasma Durability of Transparent Conducting Oxide Thin Film for Amorphous-Silicon Based Tandem Solar Cells

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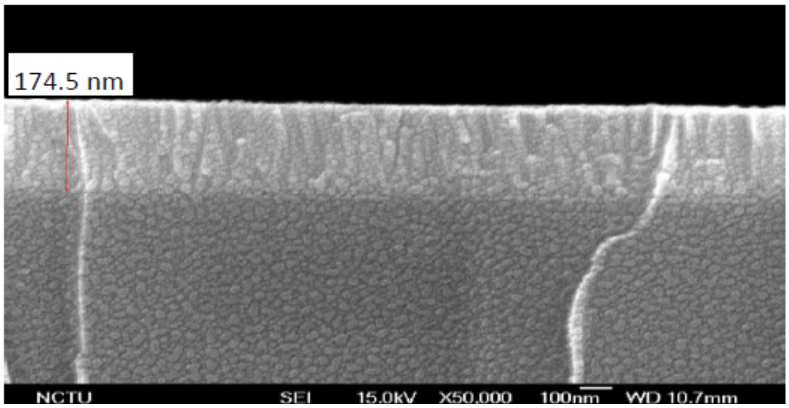
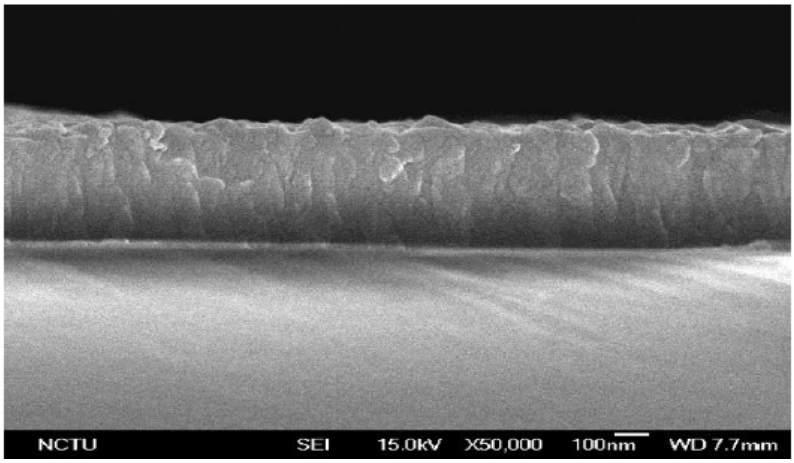
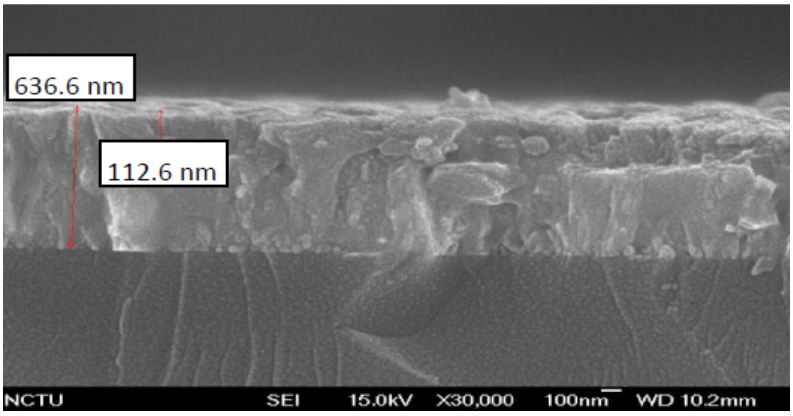


SEM cross-section of AZO

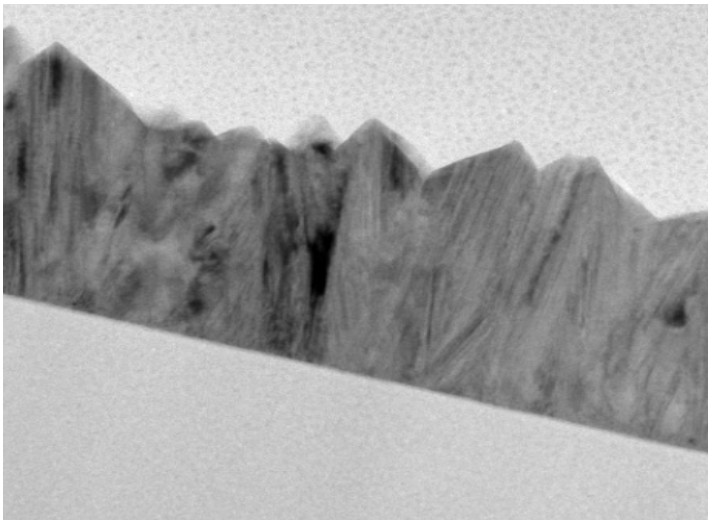


SEM cross-section of FTO

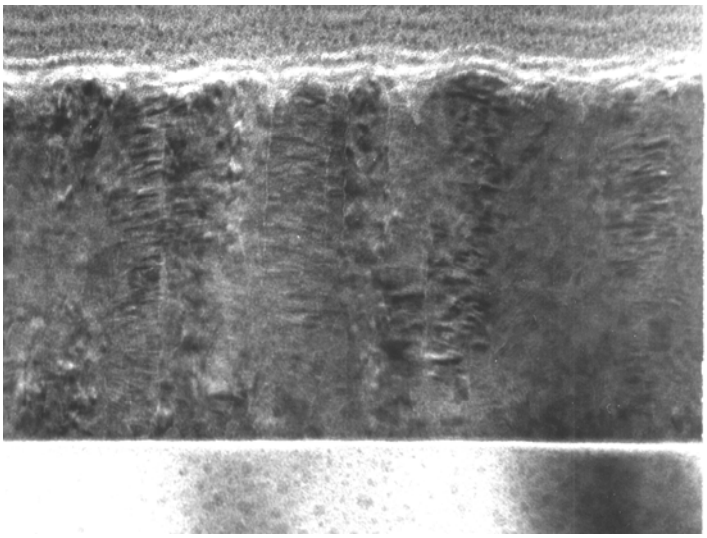


SEM cross-section of Double AZO/FTO

Figure S1 SEM cross-sectional image of AZO, F TO and Double AZO/FTO films.



TEM Cross-sectional image of FTO film



TEM Cross-sectional image of AZO film

Figure S2 TEM cross-section image of FTO and AZO films.

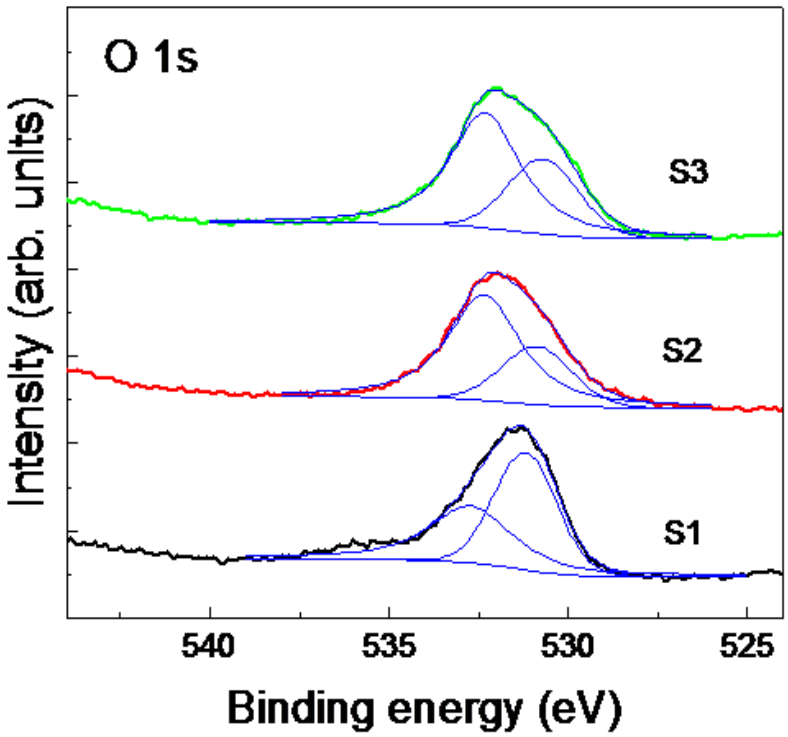


Figure S3 O1s spectra of FTO film for as-deposited films (S1), H-plasma exposed films (S2), and subsequently annealed films (S3).

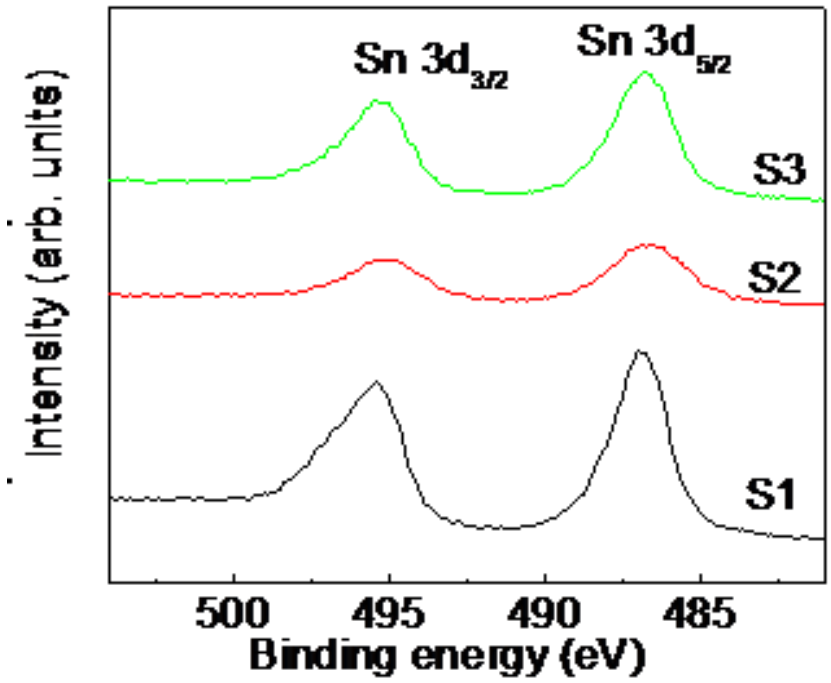


Figure S4 The relative Sn (3d3/2) and Sn (3d5/2) core level spectra of the FTO films corresponding to the surface of as-depostied films (S1), the surface of H-plasma exposed films (S2), and the surface of subsequently annealed films (S3).